AUTOMOTIVE GRADE



HEXFET® Power MOSFET

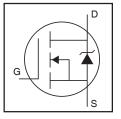
AUIRFS3307Z AUIRFSL3307Z



- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching

Features

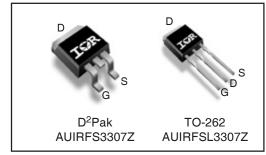
- Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified *



V _{DSS}	75V
R _{DS(on)} typ.	4.6m $Ω$
max.	5.8m Ω
I _D (Silicon Limited)	128A ①
D (Package Limited)	120A

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T_A) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	128①	
I _D @ T _C = 100°C	Continuous Drain Current, VGS @ 10V (Silicon Limited)	90①	٦ ,
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	120	
I _{DM}	Pulsed Drain Current ②	512	
P _D @T _C = 25°C	Maximum Power Dissipation	230	W
	Linear Derating Factor	1.5	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	٧
dv/dt	Peak Diode Recovery @	6.7	V/ns
E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ③	140	mJ
I _{AR}	Avalanche Current ②	See Fig. 14, 15, 22a, 22b	Α
E _{AR}	Repetitive Avalanche Energy ^⑤		mJ
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		- °C
	Soldering Temperature, for 10 seconds	300	
	(1.6mm from case)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case 9		0.65	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) , D ² Pak ®		40	C/VV

HEXFET® is a registered trademark of International Rectifier.

^{*}Qualification standards can be found at http://www.irf.com/

Static Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	75			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.094		V/°C	Reference to 25°C, I _D = 5mA ^②
R _{DS(on)}	Static Drain-to-Source On-Resistance		4.6	5.8	mΩ	$V_{GS} = 10V, I_D = 75A$ §
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 150 \mu A$
gfs	Forward Transconductance	320			S	$V_{DS} = 50V, I_D = 75A$
I _{DSS}	Drain-to-Source Leakage Current			20	μА	$V_{DS} = 75V, V_{GS} = 0V$
				250	μΑ	$V_{DS} = 75V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100	I IIA	V _{GS} = -20V
R _{G(int)}	Internal Gate Resistance		0.70		Ω	

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
Qg	Total Gate Charge		79	110		$I_D = 75A$
Q_{gs}	Gate-to-Source Charge		19		nC	$V_{DS} = 38V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		24		nc nc	V _{GS} = 10V ^⑤
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		55			$I_D = 75A, V_{DS} = 0V, V_{GS} = 10V$
t _{d(on)}	Turn-On Delay Time		15			$V_{DD} = 49V$
t _r	Rise Time		64			$I_D = 75A$
t _{d(off)}	Turn-Off Delay Time		38		ns	$R_G = 2.6\Omega$
t _f	Fall Time		65			V _{GS} = 10V ⑤
C _{iss}	Input Capacitance		4750			$V_{GS} = 0V$
Coss	Output Capacitance		420			$V_{DS} = 50V$
C _{rss}	Reverse Transfer Capacitance		190		рF	f = 1.0MHz
C _{oss} eff. (ER)	Effective Output Capacitance (Energy Related)		440			$V_{GS} = 0V$, $V_{DS} = 0V$ to $60V$ \bigcirc
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)		410		1	V _{GS} = 0V, V _{DS} = 0V to 60V [©]

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			128 ^①		MOSFET symbol	
	(Body Diode)			1200	Α	showing the	
I _{SM}	Pulsed Source Current			512	A	integral reverse	
	(Body Diode) ②⑦			312		p-n junction diode.	
V_{SD}	Diode Forward Voltage			1.3	٧	$T_J = 25^{\circ}C$, $I_S = 75A$, $V_{GS} = 0V$ $^{\circ}$	
t _{rr}	Reverse Recovery Time		33	50	ns	$T_J = 25^{\circ}C$ $V_R = 64V$,	
			39	59	115	$T_J = 125$ °C $I_F = 75A$	
Q_{rr}	Reverse Recovery Charge		42	63	nC	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s $^{\circ}$	
			56	84	110	$T_J = 125^{\circ}C$	
I _{RRM}	Reverse Recovery Current		2.2		Α	$T_J = 25^{\circ}C$	
t _{on}	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 120A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- $\textcircled{4} \quad I_{SD} \leq 75 A, \ di/dt \leq 1570 A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- $\ \, \mbox{(\^{S})} \, \, \mbox{C}_{OSS}$ eff. (TR) is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 80% V_{DSS} .
- \odot C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.



Qualification	Information [†]				
		Automotive			
			(per AEC-Q101) ††		
Qualification Level Comments: This part number(s) pass		IR's Industrial and Consumer el is granted by extension of the			
Maiahan Canaikinika Lanai		3L-D2 PAK	MSL1		
Moisture Sensit	livity Level	3L-TO-262 N/A			
	Machine Model	Class M4(+/- 800V) ^{†††}			
	Wachine Woder	(per AEC-Q101-002)			
505	Llamana Dada Madal	Class H1C(+/- 2000V)†††			
ESD Human Body Model		(per AEC-Q101-001)			
	S. 15 . M. 1		Class C5(+/- 2000V) ^{†††}		
Charged Device Model		(per AEC-Q101-005)			
RoHS Complian	nt	Yes			

[†] Qualification standards can be found at International Rectifier's web site: http://www.irf.com/

^{††} Exceptions (if any) to AEC-Q101 requirements are noted in the qualification report.

^{†††} Highest passing voltage

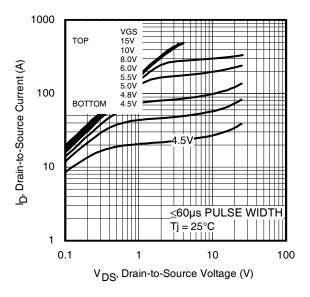


Fig 1. Typical Output Characteristics

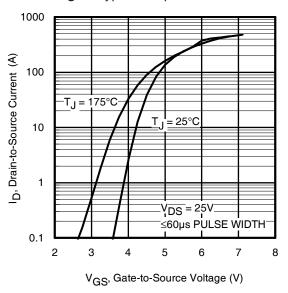


Fig 3. Typical Transfer Characteristics

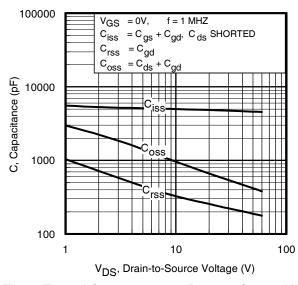


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

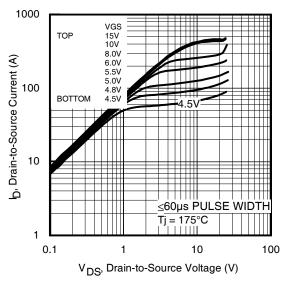


Fig 2. Typical Output Characteristics

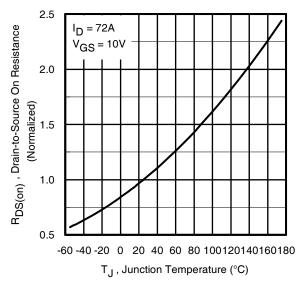


Fig 4. Normalized On-Resistance vs. Temperature

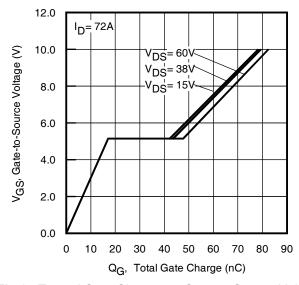


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage www.irf.com

4

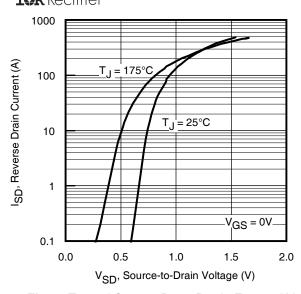


Fig 7. Typical Source-Drain Diode Forward Voltage

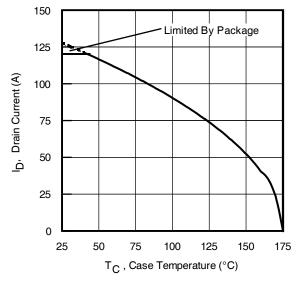


Fig 9. Maximum Drain Current vs. Case Temperature

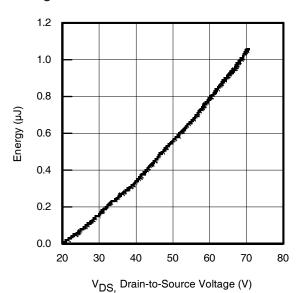


Fig 11. Typical C_{OSS} Stored Energy

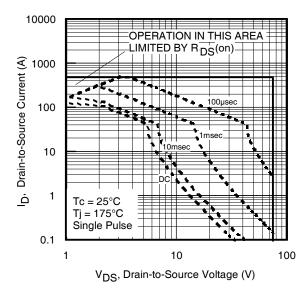


Fig 8. Maximum Safe Operating Area

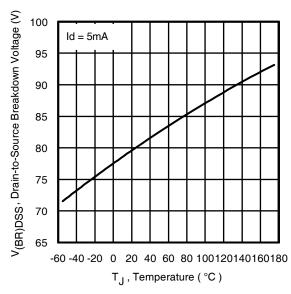


Fig 10. Drain-to-Source Breakdown Voltage

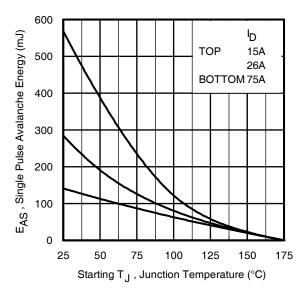


Fig 12. Maximum Avalanche Energy vs. DrainCurrent

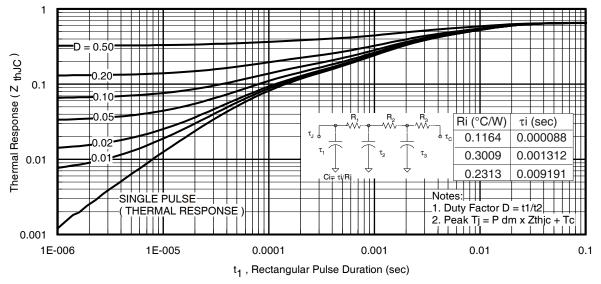


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

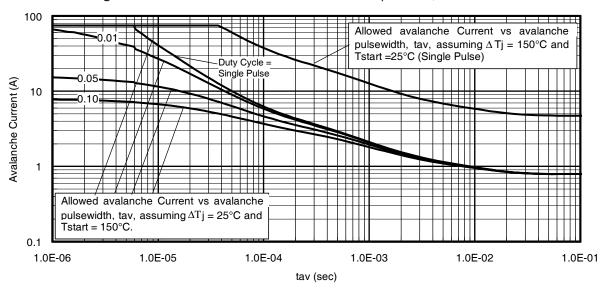


Fig 14. Typical Avalanche Current vs. Pulsewidth

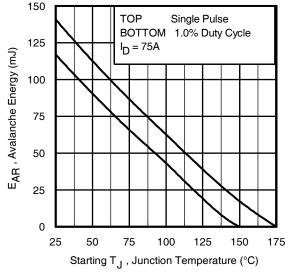


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{imax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- BV = Aated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

t_{av =} Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

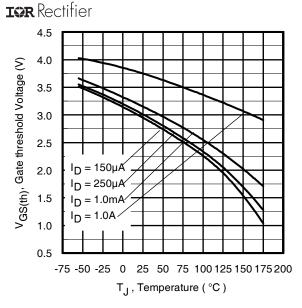


Fig 16. Threshold Voltage vs. Temperature

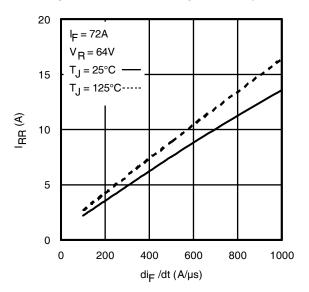


Fig. 18 - Typical Recovery Current vs. dif/dt

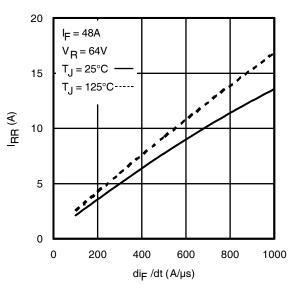


Fig. 17 - Typical Recovery Current vs. di_f/dt

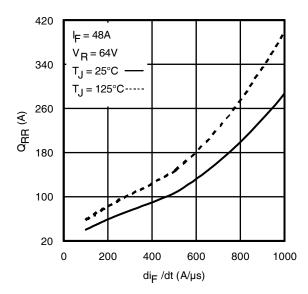


Fig. 19 - Typical Stored Charge vs. di_f/dt

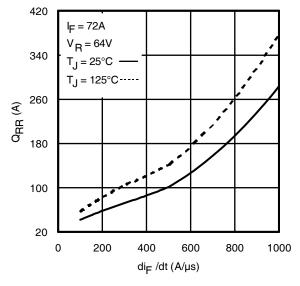


Fig. 20 - Typical Stored Charge vs. dif/dt

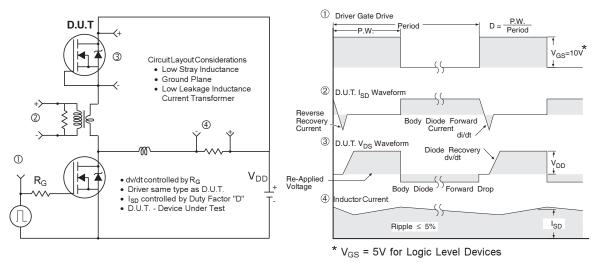


Fig 20. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

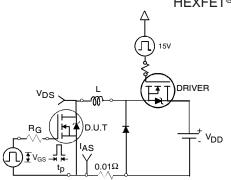


Fig 21a. Unclamped Inductive Test Circuit

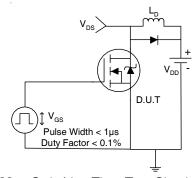


Fig 22a. Switching Time Test Circuit

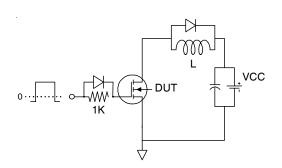


Fig 23a. Gate Charge Test Circuit

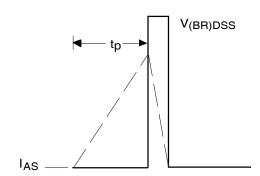


Fig 21b. Unclamped Inductive Waveforms

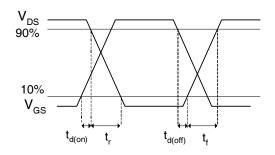


Fig 22b. Switching Time Waveforms

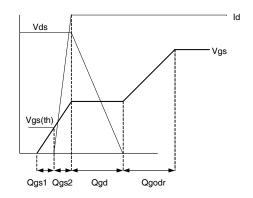
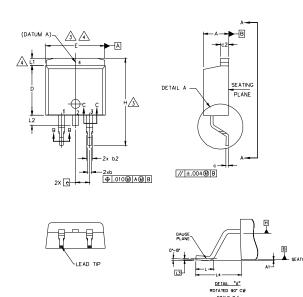
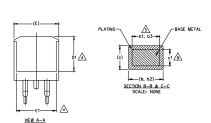


Fig 23b. Gate Charge Waveform

D²Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)





NOTES:

- 1, DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND 61 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

Z -		DIMENSIONS					
M B O	MILLIM	ETERS	INCHES		O T E S		
L	MIN.	MAX.	MIN.	MAX.	S		
Α	4.06	4.83	.160	.190			
A1	0.00	0.254	.000	.010			
b	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1,14	1.78	.045	.070			
b3	1,14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1,14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6,86	-	.270		4		
Ε	9.65	10.67	.380	.420	3,4		
E1	6.22	-	.245		4		
e	2.54	BSC	.100	BSC			
Н	14.61	15.88	.575	.625			
L	1.78	2.79	.070	.110			
L1	-	1.65	-	.066	4		
L2	1.27	1.78	_	.070			
L3	0.25	BSC	.010	BSC			
L4	4.78	5.28	.188	.208			

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE 2, 4.- DRAIN 3.- SOURCE

IGBTs, CoPACK

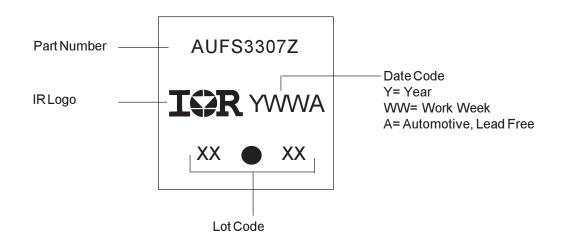
1.- GATE
2, 4.- COLLECTOR
3.- EMITTER

DIODES

1.- ANODE *
2. 4.- CATHODE
3.- ANODE

* PART DEPENDENT.

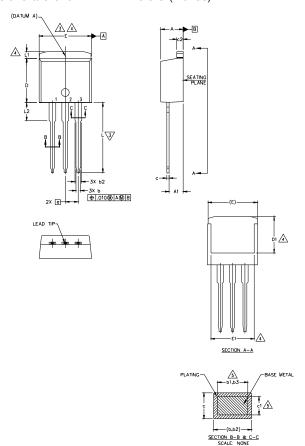
D²Pak Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14,5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S			Ŋ		
M B O L	MILLIM	ETERS	RS INCHES		
L	MIN.	MAX.	MIN.	MAX.	N O T E S
Α	4.06	4.83	.160	.190	
A1	2.03	3.02	.080	.119	
b	0.51	0.99	.020	.039	
b1	0.51	0,89	.020	.035	5
b2	1,14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1,14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	-	4
Ε	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
е	2,54	BSC	.100	BSC	
L	13,46	14.10	.530	.555	
L1	-	1.65	-	.065	4
L2	3.56	3,71	.140	.146	

LEAD ASSIGNMENTS

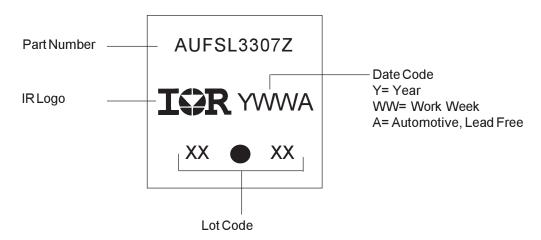
HEXFET

- 1 GATE
- 2.- DRAIN 3.- SOURCE 4.- DRAIN

IGBTs, CoPACK

- 1.- GATE
 2.- COLLECTOR
 3.- EMITTER
 4.- COLLECTOR

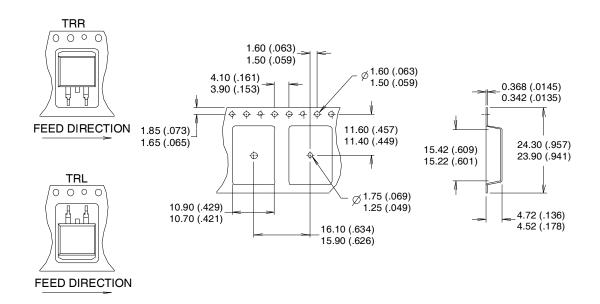
TO-262 Part Marking Information

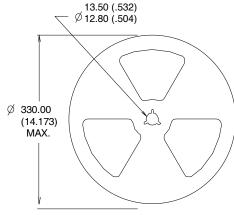


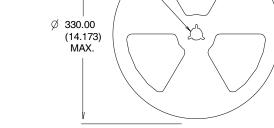
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

D²Pak (TO-263AB) Tape & Reel Information

Dimensions are shown in millimeters (inches)

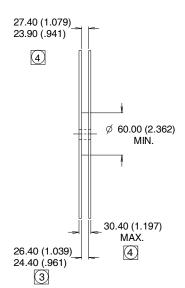






NOTES:

- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.



Ordering Information

Base part	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRFSL3307Z	TO-262	Tube	50	AUIRFSL3307Z
AUIRFS3307Z	D2Pak	Tube	50	AUIRFS3307Z
		Tape and Reel Left	800	AUIRFS3307ZTRL
		Tape and Reel Right	800	AUIRFS3307ZTRR

IMPORTANT NOTICE

Unless specifically designated for the automotive market, International Rectifier Corporation and its subsidiaries (IR) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or services without notice. Part numbers designated with the "AU" prefix follow automotive industry and / or customer specific requirements with regards to product discontinuance and process change notification. All products are sold subject to IR's terms and conditions of sale supplied at the time of order acknowledgment.

IR warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with IR's standard warranty. Testing and other quality control techniques are used to the extent IR deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

IR assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using IR components. To minimize the risks with customer products and applications, customers should provide adequate design and operating safeguards.

Reproduction of IR information in IR data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alterations is an unfair and deceptive business practice. IR is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of IR products or serviced with statements different from or beyond the parameters stated by IR for that product or service voids all express and any implied warranties for the associated IR product or service and is an unfair and deceptive business practice. IR is not responsible or liable for any such statements.

IR products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or in other applications intended to support or sustain life, or in any other application in which the failure of the IR product could create a situation where personal injury or death may occur. Should Buyer purchase or use IR products for any such unintended or unauthorized application, Buyer shall indemnify and hold International Rectifier and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that IR was negligent regarding the design or manufacture of the product.

Only products certified as military grade by the Defense Logistics Agency (DLA) of the US Department of Defense, are designed and manufactured to meet DLA military specifications required by certain military, aerospace or other applications. Buyers acknowledge and agree that any use of IR products not certified by DLA as military-grade, in applications requiring military grade products, is solely at the Buyer's own risk and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

IR products are neither designed nor intended for use in automotive applications or environments unless the specific IR products are designated by IR as compliant with ISO/TS 16949 requirements and bear a part number including the designation "AU". Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, IR will not be responsible for any failure to meet such requirements.

For technical support, please contact IR's Technical Assistance Center

http://www.irf.com/technical-info/

WORLDHEADQUARTERS:

101 N. Sepulveda Blvd., El Segundo, California 90245

Tel: (310) 252-7105